

**LIST OF PRIOR ART CITED BY
APPLICANT
(PTO-1449)**

ATTY. DOCKET NO.
LGS/S-0030A

APPLN. SERIAL NO.
Divisional of
09/290,891

APPLICANT(S)
Joo-Hyong LEE

FILING DATE
September 19, 2001

GROUP
Art Unit

31011 U.S. PTO
 09/19/01
 09/19/01

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
<i>P</i>	5,677,209	10/1997	SHON et al.	148	DIG. 10	
<i>P</i>	5,966,599	10/1999	WALKER et al.	438	228	
<i>P</i>	5,963,798	10/1999	KIM et al.	438	199	
<i>P</i>	5,010,034	04/1991	MANOLIU	438	207	
<i>P</i>	5,013,671	05/1991	HAVEMANN	148	DIG. 10	
<i>P</i>	5,047,357	09/1991	EKLUND	438	207	
<i>P</i>	5,342,794	08/1994	WEI	438	374	
<i>P</i>	5,407,840	04/1995	MANOLIU et al.	438	202	
<i>P</i>	5,436,176	07/1995	SHIMIZU et al.	438	526	
<i>P</i>	6,069,048	05/2000	DANIEL	438	370	
<i>P</i>	5,877,049	03/1999	LIU et al.	438	224	

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
	/		/			

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
	/		/			

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	/		/				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

<i>P</i>	Ajith Amerasekera et al., "Designing Latchup Robustness in a 0.35 μ m Technology", IEEE/IRPS 1994, pp. 280-283.

EXAMINER

DATE CONSIDERED

6/17/02

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
<i>[Handwritten initials]</i>	5,899,714	05/1999	FARRENKOPF et al.	438	202	
	5,840,603	11/1998	SAKAMOTO	438	202	
	5,622,885	04/1997	MERRILL et al.	438	220	
	4,859,630	08/1989	JOSQUIN	438	234	
	5,338,986	08/1994	KURIMOTO	327	566	
	5,831,313	11/1998	HAN et al.	257	371	
	5,960,277	09/1999	BLANCHARD	438	234	
	4,877,748	10/1989	HAVEMANN	438	371	
	4,408,387	10/1983	KIRISEKO	438	372	
	5,441,900	08/1995	BULUCEA et al.	438	199	

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

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